

**Section 2. Forms PTO/SB/08A and 08B (formerly Form PTO-1449)****IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Hess et al. Attorney Docket: 2119/103  
 Serial No: 09/842,361 Art Group Unit: 1743  
 Date Filed: April 25, 2001 Examiner Name: Not yet assigned  
 Invention: A System and Method for High Throughput Processing of Droplets

**LIST OF PATENTS AND PUBLICATIONS FOR  
 APPLICANT'S INFORMATION DISCLOSURE STATEMENT**

**United States Patents**

Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
	AA	3,566,677	06/26/69	Cole et al.	73-61.3
	AB	3,734,622	05/22/73	Adler, Stanford L.	356/103
	AC	4,071,315	01/31/78	Chateau, Guy	23/230
	AD	4,111,553	09/05/78	Garnys, Vytenis Peter	356/36
	AE	4,659,677	04/21/87	Glover et al.	436/174
	AF	4,837,160	06/06/89	Meserol et al.	436/45
	AG	4,841,145	06/20/89	Wada et al.	250/304
	AH	4,883,642	11/28/89	Bisconte, Jean- Claude	422/66
	AI	5,006,749	04/09/91	White, Richard M.	310/323
	AJ	5,334,837	08/02/94	Ikeda et al.	250/339
	AK	5,486,337	01/23/96	Ohkawa, Tihiro	422/100
	AL	5,516,692	05/14/96	Berndt, Klaus W.	435/286.7

**International Patents**

Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
	AM	EP60022478	04.02.85	Toshio, Shinsei	H02N 2/00
	AN	EP0556748 A2	12.02.93	Nishimura et al.	G01N 15/14

5/16/05

<u>Jo</u>	AO	WO9534374	21.12.95	Bryning et al.	G01N 21/86
<u>I</u>	AP	EP0752281	17.05.96	Pezzoli et al.	B07C 5/36
<u>I</u>		A2			
<u>I</u>	AQ	WO9808093	26.02.98	Kouvonen, Ilkka	G01N 33/543
<u>Ja</u>	AR	WO9815355	16.04.98	Dannoux, Thierry	B01L

Examiner Signature:

Date Considered:

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation *if not* in conformance and not considered. Include copy of this form with next communication to applicant.

02119/00103 173355.1

Jo 5/16/05

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In re application of: Hess et al.

Application No.: 09/842,361

Group Art Unit: 1743

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Examiner: Jeffrey Snay

For: A System and Method for High Throughput Processing of Droplets

**LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS'  
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

**United States Patents**

Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
<u>JS</u>	AS	5,191,212	03/02/93	Falk et al.	250/288
<u>JS</u>	AT	5,508,200	04/16/96	Tiffany et al.	436/44

**Foreign Patent Documents**

Examiner Initials	Reference Number	Document Number	Issue Date	Class/Subclass
<u>JS</u>	AU	WO 99/11373	03/11/99	B01L 3/02
<u>JS</u>	AV	EP 0 983 788 A2	03/08/00	B01F 13/00
<u>JS</u>	AW	WO 00/63705	10/26/00	G01N 35/00
<u>JS</u>	AX	FR 2 820 058	08/02/02	B01L 3/00

**Other Documents**

Examiner Initials	Reference Number	Author	Title of Article, Title of Item, Date, Page(s), Volume- Issue Number(s)
<u>JS</u>	AY	Niessen	Advances in instrumentation in liquid chromatography – mass spectrometry and related liquid-introduction techniques, Journal of Chromatography A. 794 (1998) 407-435

Examiner Signature: JS

Date Considered: 5/16/05

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Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
	AZ	WO 00/45929	08/10/00	Pidgeon et al.	B01D 15/08

Examiner Signature: 

Date Considered: 

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